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FCH104N60F_F085

N-Channel SuperFET II FRFET MOSFET 600 V, 37 A, 104 mΩ

Features

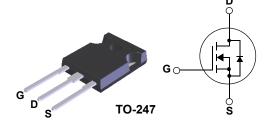
- Typical $R_{DS(on)}$ = 91 m Ω at V_{GS} = 10 V, I_D = 18.5 A
- Typical $Q_{\alpha(tot)}$ = 109 nC at V_{GS} = 10V, I_D = 18.5 A
- UIS Capability
- Qualified to AEC Q101
- RoHS Compliant

Description

SuperFET® II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently SuperFETII is very well suited for the Soft switching

and Hard Switching topologies like High Voltage Full Bridge and Half Bridge DC-DC, Interleaved Boost PFC, Boost PFC for HEV-EV automotive.

SuperFET II FRFET® MOSFET's optimized body diode reverse recovery performance can remove additional component and improve system reliability.



For current package drawing, please refer to the Fairchild website at https://www.fairchildsemi.com/package-drawings/TO/ TO247A03.pdf

Application

- Automotive On Board Charger
- Automotive DC/DC converter for HEV



November 2014

Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain to Source Voltage		600	V
V_{GS}	Gate to Source Voltage		±20	V
		T _C = 25°C	37	Α
I_D	Drain Current - Continuous (V _{GS} =10) (Note 1)	T _C = 100°C	24	Α
	Pulsed Drain Current		See Fig 4	Α
E _{AS}	Single Pulse Avalanche Rating	(Note 2)	809	mJ
dv/dt	MOSFET dv/dt		100	1//20
uv/ut	Peak Diode Recovery dv/dt	(Note 3)	50	V/ns
0	Power Dissipation		357	W
P_D	Derate Above 25°C		2.85	W/°C
T _J , T _{STG}	Operating and Storage Temperature		-55 to + 150	°C
$R_{\theta JC}$	Maximum Thermal Resistance Junction to Case		0.35	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance Junction to Ambie	ent (Note 4)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCH104N60F	FCH104N60F F085	TO-247	-	-	30

Notes:

- 1: Current is limited by bondwire configuration.
- 2: Starting T_J = 25°C, L = 35mH, I_{AS} = 6.8A, V_{DD} = 100V during inductor charging and V_{DD} = 0V during time in avalanche. 3: I_{SD} ≤ 18.5A, di/dt ≤ 200 A/us, V_{DD} ≤ 380V, starting T_J = 25°C.
- 4: R_{0,JA} is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in² pad of 2oz copper.

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units		
Off Cha	Off Characteristics							
Bypee	Drain to Source Breakdown Voltage	In = 250µA Vos = 0V	600	_	_	V		

	B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V$	_{GS} = 0V	600	-	-	V
	1	Drain to Source Leakage Current	V _{DS} =600V,	$T_J = 25^{\circ}C$	-	-	10	μΑ
I _{DSS} Drain to Source Leakage Current	$V_{GS} = 0V$	$T_J = 150^{\circ}C(Note 5)$	-	-	1	mA		
	I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{DS}$	₀ = 250μA	3.0	4.0	5.0	V
r _{DS(on)} Drain to Source On Resistance	I _D = 18.5A,	$T_{\rm J} = 25^{\rm o}{\rm C}$	-	91	104	$m\Omega$	
	$V_{GS} = 10V$	$T_J = 150^{\circ}C(Note 5)$	-	217	275	mΩ	

Dynamic Characteristics

C _{iss}	Input Capacitance	1001/1/ 01/	-	4302	-	pF
C _{oss}	Output Capacitance	$V_{DS} = 100V, V_{GS} = 0V,$ f = 1MHz	-	134	-	pF
C _{rss}	Reverse Transfer Capacitance		-	1.7	-	pF
R_g	Gate Resistance	f = 1MHz	-	0.49	-	Ω
$Q_{g(ToT)}$	Total Gate Charge	.,	-	109	139	nC
$Q_{g(th)}$	Threshold Gate Charge	V _{DD} = 380V I _D = 18.5A V _{GS} = 10V	-	8	11	nC
Q_{gs}	Gate to Source Gate Charge		-	23	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		-	46	-	nC

Switching Characteristics

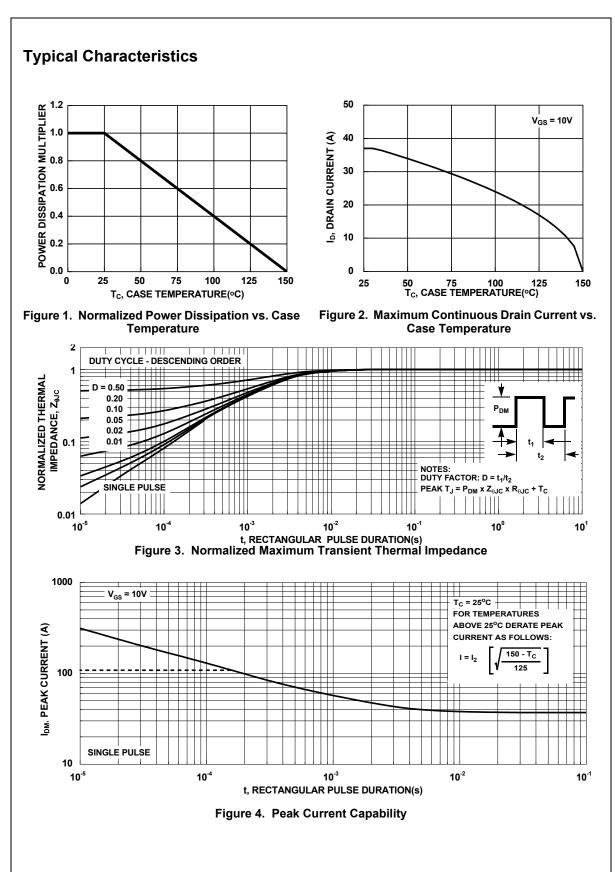
t _{on}	Turn-On Time		-	58	78	ns
t _{d(on)}	Turn-On Delay Time	V_{DD} = 380V, I_{D} = 18.5A, V_{GS} = 10V, R_{G} = 4.7 Ω	-	35	ı	ns
t _r	Rise Time		-	23	-	ns
t _{d(off)}	Turn-Off Delay Time		-	94	-	ns
t _f	Fall Time		-	5	-	ns
t _{off}	Turn-Off Time		-	98	131	ns

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Voltage	I _{SD} = 18.5A, V _{GS} = 0V	-	-	1.2	V
T _{rr}	Reverse Recovery Time	$I_F = 18.5A$, $dI_{SD}/dt = 100A/\mu s$	-	162	-	ns
Q_{rr}	Reverse Recovery Charge	V _{DD} = 480V	-	1223	-	nC

Notes

5: The maximum value is specified by design at T_J = 150°C. Product is not tested to this condition in production.



Typical Characteristics

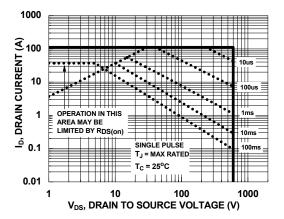


Figure 5. Forward Bias Safe Operating Area

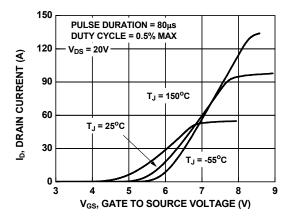


Figure 6. Transfer Characteristics

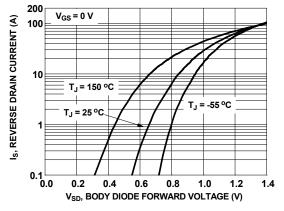


Figure 7. Forward Diode Characteristics

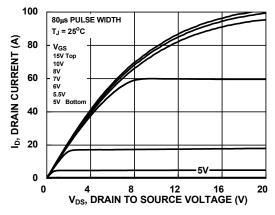


Figure 8. Saturation Characteristics

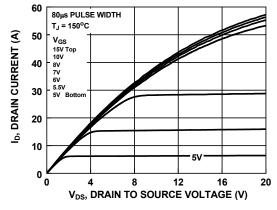


Figure 9. Saturation Characteristics

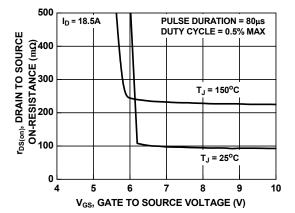


Figure 10. R_{DSON} vs. Gate Voltage

Typical Characteristics

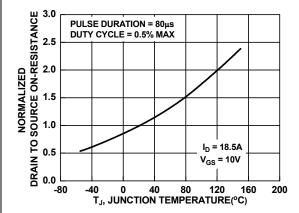


Figure 11. Normalized R_{DSON} vs. Junction Temperature

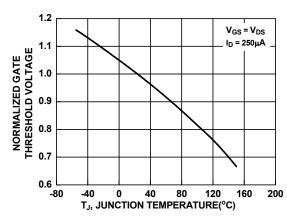


Figure 12. Normalized Gate Threshold Voltage vs.
Temperature

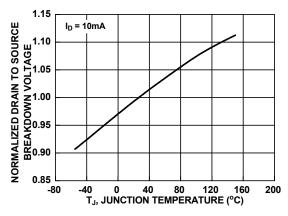


Figure 13. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

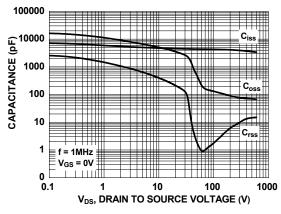


Figure 14. Capacitance vs. Drain to Source Voltage

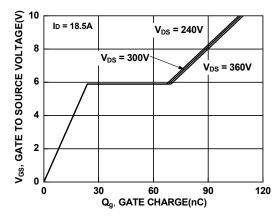


Figure 15. Gate Charge vs. Gate to Source Voltage

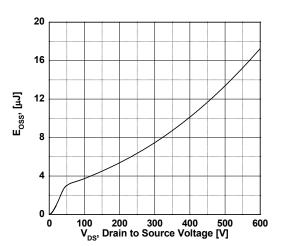


Figure 16. Eoss vs. Drain to Source Voltage

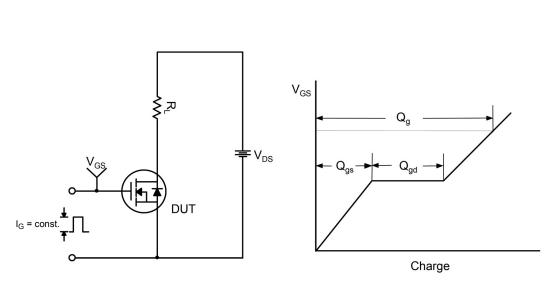


Figure 17. Gate Charge Test Circuit & Waveform

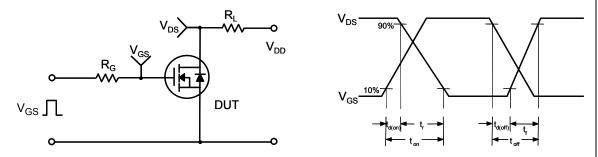


Figure 18. Resistive Switching Test Circuit & Waveforms

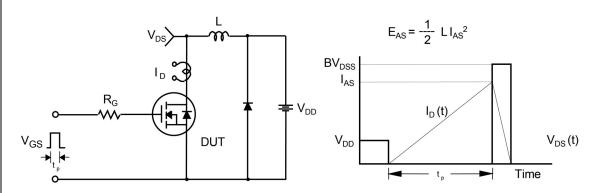
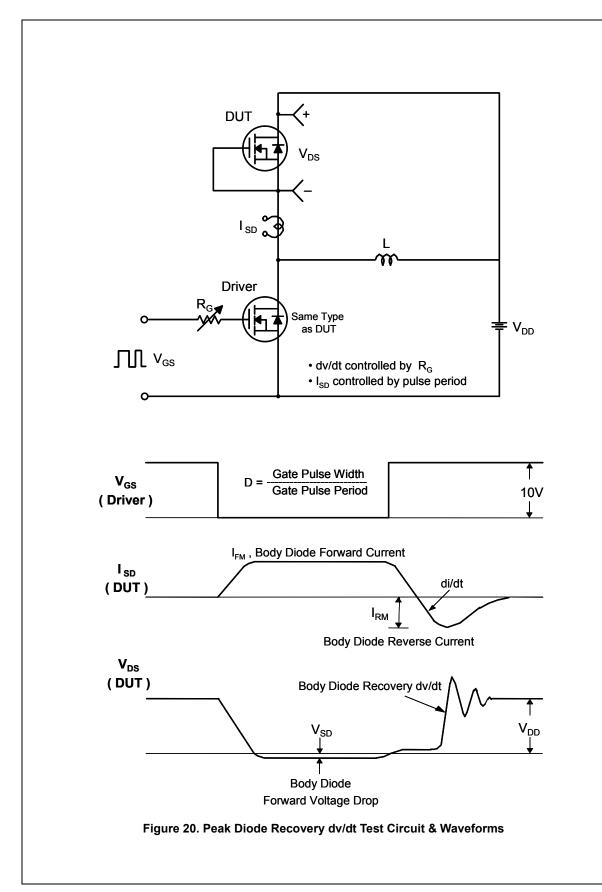
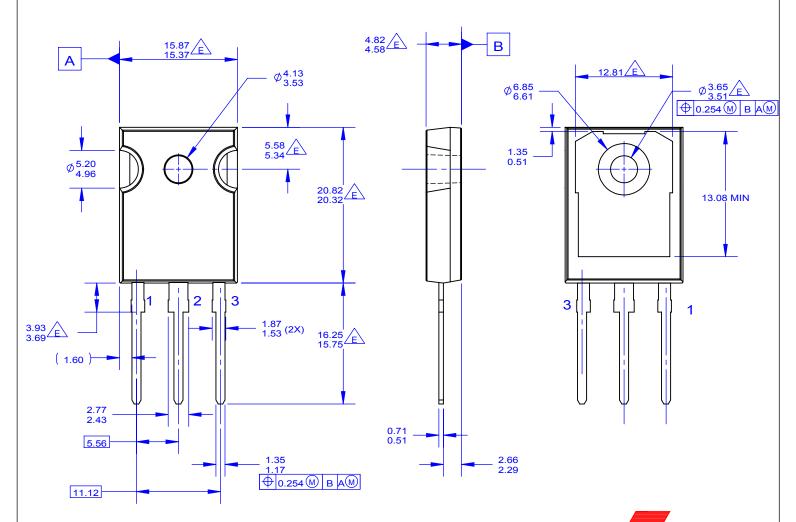


Figure 19. Unclamped Inductive Switching Test Circuit & Waveforms







NOTES: UNLESS OTHERWISE SPECIFIED.

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